

One bin test (on-off problem)

A counting expt. observed events $\rightarrow n$, $n = \underline{\underline{\eta_s}} + \underline{\underline{\eta_b}}$

$$\underline{E}(n) = \boxed{\mu s} + \boxed{b}$$

↑ signal strength parameter (p.o.i)

b \Rightarrow nuisance parameter

s \Rightarrow comes from theory.

Two hypotheses : $\mu = 0$ background only
 $\mu \neq 0$ signal + background.

null

$$\mu = 0 : P(n | b) = \frac{e^{-b} b^n}{n!}$$

$$\mu \neq 0 : P(n | \mu s + b) = \frac{e^{-\mu s + b} (\mu s + b)^n}{n!}$$

b is constrained by a control measurement
 (let's say, an MC estimate of b)

m counts in control sample.

$$\underline{E}(m) = \underline{\tau b} \quad (\text{Assume, } \underline{\tau} \text{ is known})$$



Joint prob of observing (n, m)

$$L(\mu, b) = \left[\frac{(\mu s + b)^n e^{-(\mu s + b)}}{n!} \right] \left[\frac{(\tau b)^m e^{-\tau b}}{m!} \right]$$

real run auxiliary

When $\mu \neq 0$

$$\left. \begin{aligned} \frac{\partial L}{\partial \mu} = 0 \\ \frac{\partial L}{\partial b} = 0 \end{aligned} \right\} \Rightarrow$$

$$\hat{\mu} = \frac{n - \frac{m}{\tau}}{s}$$

$$\hat{b} = \frac{m}{\tau}$$

↑ post-fit. estimates

When μ is not allowed to vary, but kept at some specified value (profiling)

$$\hat{b} = \frac{(n+m) - (1+\tau)\mu S}{2(1+\tau)} + \left[\frac{(n+m - (1+\tau)\mu S)^2 + 4(1+\tau)m\mu S}{4(1+\tau)^2} \right]^{1/2}$$

in particular, for $\mu = 0$

$$\hat{b} = \frac{(n+m)}{2(1+\tau)} + \frac{(n+m)}{2(1+\tau)} = \frac{n+m}{1+\tau}$$

: Weighted average of the two counts.

We construct a test statistic

$$\lambda(\mu) = \frac{L(\mu, \hat{b})}{L(\hat{\mu}, \hat{b})}$$

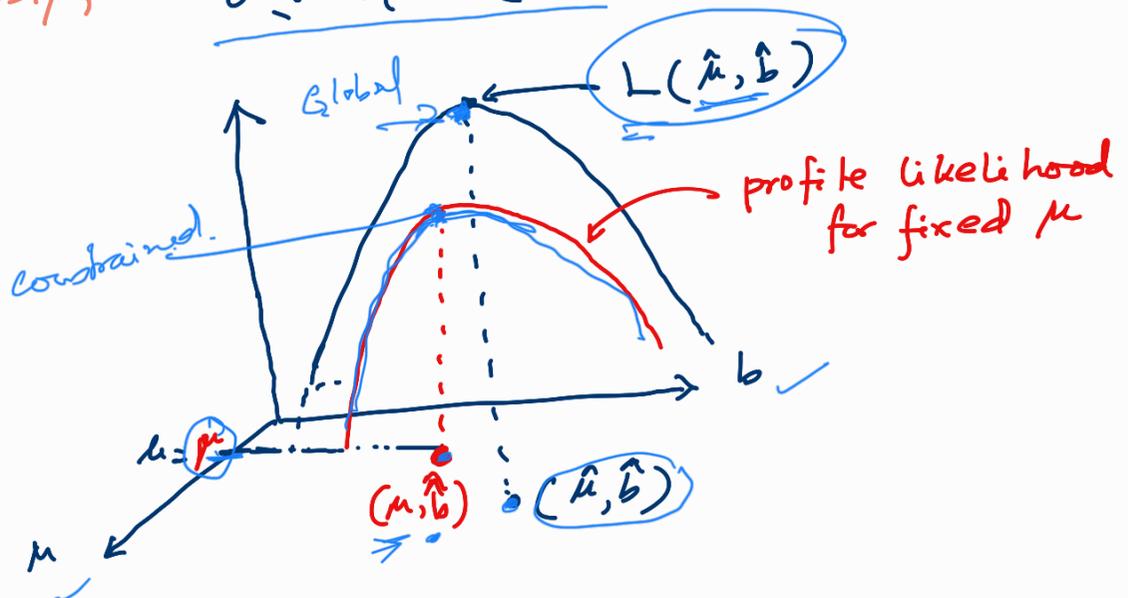
μ

← conditional max
← unconditional max

* "statistic means a function of data"

profile L.R.

Obviously, $0 \leq \lambda(\mu) \leq 1$



$$t_\mu = -2 \ln \lambda(\mu)$$

↑ statistic, random.

